

330

Accession number:20114814563035

Title:Erratum: Improved sample characterization in terahertz reflection imaging and spectroscopy (Optical Society of America (2009) 17:5 (3848-3854))

Authors:Huang, Shengyang (1); Ashworth, Philip C. (2); Kan, Kanis Wai Chi (1); Chen, Yang (1); Wallace, Vincent P. (4); Zhang, Yuan-Ting (1); Pickwell-Macpherson, Emma (1)

Author affiliation:(1) Department of Electronic Engineering, Chinese University of Hong Kong, NT, Hong Kong, Hong Kong; (2) Semiconductor Physics Group, Cavendish Laboratory, University of Cambridge, JJ Thompson Ave., Cambridge, CB3 0HE, United Kingdom; (3) TeraView Ltd., Platinum Building, St. John's Innovation Park, CB4 0WS, United Kingdom; (4) Optical and Biomedical Engineering Laboratory, University of Western Australia, Perth, Australia

Corresponding author:Pickwell-Macpherson, E.(emma@ee.cuhk.edu.hk)

Source title:Optics Express

Abbreviated source title:Opt. Express

Volume:19

Issue:24

Issue date:November 21, 2011

Publication year:2011

Pages:24782

Language:English

E-ISSN:10944087

Document type:Journal article (JA)

Publisher:Optical Society of America, 2010 Massachusetts Avenue NW, Washington, DC 20036-1023, United States

Number of references:1